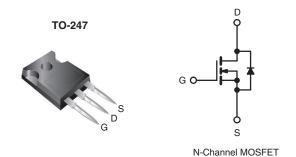


Power MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	60	60				
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	0.018				
Q _g (Max.) (nC)	110	0				
Q _{gs} (nC)	29)				
Q _{gd} (nC)	38	3				
Configuration	Sing	Single				



FEATURES

- Dynamic dV/dt Rating
- · Isolated Central Mounting Hole
- 175 °C Operating Temperature
- · Ease of Paralleling
- · Simple Drive Requirements
- Lead (Pb)-free Available



DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because its isolated mounting hole. It also provides greater creepage distances between pins to meet the requirements of most safety specifications.

ORDERING INFORMATION	
Package	TO-247
Lead (Pb)-free	IRFP048PbF
Leau (FD)-liee	SiHFP048-E3
SnPb	IRFP048
SIFD	SiHFP048

PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V_{DS}	60	V
Gate-Source Voltage			V_{GS}	± 20	7 v
Continuous Drain Current ^e	V _{GS} at 10 V	$T_{\rm C} = 25 ^{\circ}{\rm C}$ $T_{\rm C} = 100 ^{\circ}{\rm C}$	I _D	70	А
Continuous Drain Current		T _C = 100 °C		52	
Pulsed Drain Current ^a			I _{DM}	290	
Linear Derating Factor				1.3	W/°C
Single Pulse Avalanche Energy ^b			E _{AS}	200	mJ
Maximum Power Dissipation	T _C =	25 °C	P_{D}	190	W
Peak Diode Recovery dV/dt ^c			dV/dt	4.5	V/ns
perating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 175	°C
Soldering Recommendations (Peak Temperature) ^d	for 10 s			300	7
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in
				1.1	N · m

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. V_{DD} = 25 V, starting T_J = 25 °C, L = 43 μ H, R_G = 25 Ω , I_{AS} = 73 A (see fig. 12).
- c. $I_{SD} \leq 72$ A, $dI/dt \leq 200$ A/µs, $V_{DD} \leq V_{DS}, \, T_J \leq 175$ °C.
- d. 1.6 mm from case.
- e. Current limited by the package (die current = 73 A).

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply

IRFP048, SiHFP048

Vishay Siliconix



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	40		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.80		

PARAMETER	SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0	60	-	-	٧	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference t	o 25 °C, I _D = 1 mA	-	0.060	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{c}$	_{GS} , I _D = 250 μA	2.0	-	4.0	٧
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20 V		-	-	± 100	nA
Zone Ooto Walkers Busin Oursel	I _{DSS}	V _{DS} = 60 V, V _{GS} = 0 V		-	-	25	
Zero Gate Voltage Drain Current		V _{DS} = 48 V, V ₀	_{GS} = 0 V, T _J = 150 °C	-	-	250	μΑ
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 44 A ^b	-	-	0.018	Ω
Forward Transconductance	9 _{fs}	V _{DS} = 25 V, I _D = 44 A ^b		20	-	-	S
Dynamic							
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ $f = 1.0 \text{ MHz}, \text{ see fig. 5}$		-	2400	-	pF
Output Capacitance	C _{oss}			-	1300	-	
Reverse Transfer Capacitance	C _{rss}			-	190	-	
Total Gate Charge	Qg		V _{GS} = 10 V	-	-	110	nC
Gate-Source Charge	Q_{gs}	V _{GS} = 10 V		-	-	29	
Gate-Drain Charge	Q _{gd}	See lig. 0 and 10	-	-	38		
Turn-On Delay Time	t _{d(on)}	$V_{DD} = 30 \text{ V}, I_D = 72 \text{ A},$ $R_G = 9.1 \Omega, R_D = 0.34 \Omega, \text{ see fig. } 10^b$		-	8.1	-	- ns
Rise Time	t _r			-	250	-	
Turn-Off Delay Time	t _{d(off)}			-	210	-	
Fall Time	t _f			-	250	-	
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	- nH
Internal Source Inductance	L _S			-	13	-	
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	70 ^c	Α
Pulsed Diode Forward Current ^a	I _{SM}			-	-	290	
Body Diode Voltage	V_{SD}	$T_J = 25 ^{\circ}\text{C}, I_S = 73 \text{A}, V_{GS} = 0 \text{V}^{\text{b}}$		-	-	2.0	V
Body Diode Reverse Recovery Time	t _{rr}	$T_J = 25 ^{\circ}\text{C}, I_F = 72 \text{A}, dI/dt = 100 \text{A/}\mu\text{s}^b$		-	120	180	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	0.50	0.80	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D					L _D)

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 $\mu s;$ duty cycle \leq 2 %.
- c. Current limited by the package (die current = 73 A).



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

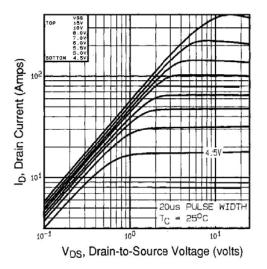


Fig. 1 - Typical Output Characteristics, $T_C = 25$ °C

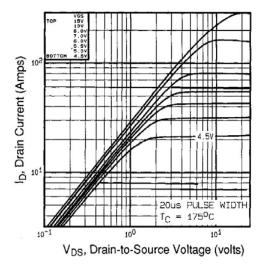


Fig. 2 - Typical Output Characteristics, $T_C = 175$ °C

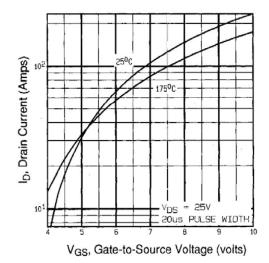


Fig. 3 - Typical Transfer Characteristics

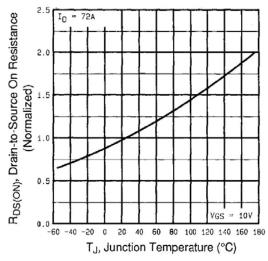


Fig. 4 - Normalized On-Resistance vs. Temperature



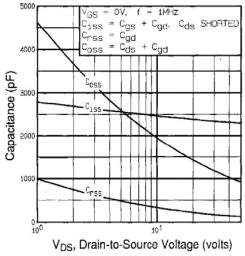


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

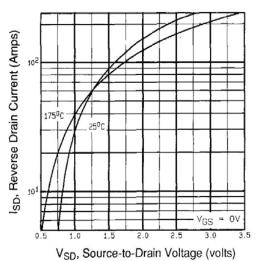


Fig. 7 - Typical Source-Drain Diode Forward Voltage

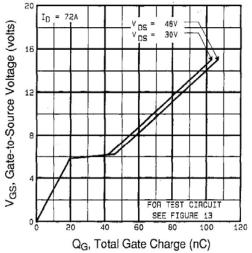


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

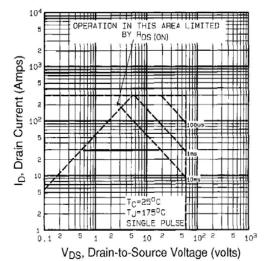


Fig. 8 - Maximum Safe Operating Area



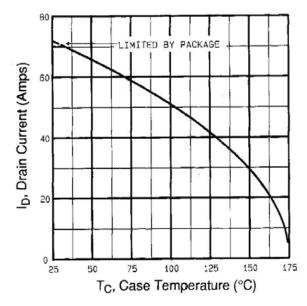


Fig. 9 - Maximum Drain Current vs. Case Temperature

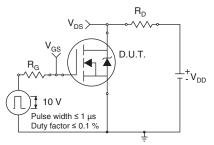


Fig. 10a - Switching Time Test Circuit

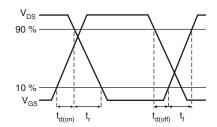


Fig. 10b - Switching Time Waveforms

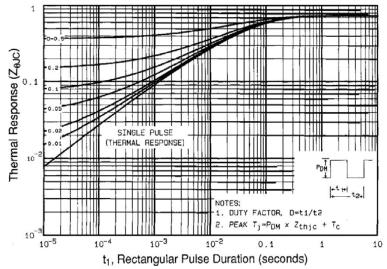


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



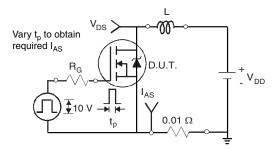


Fig. 12a - Unclamped Inductive Test Circuit

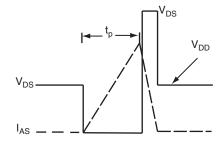


Fig. 12b - Unclamped Inductive Waveforms

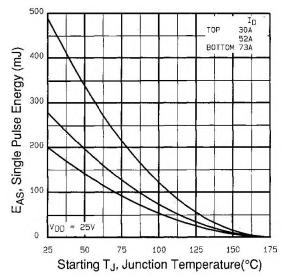


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

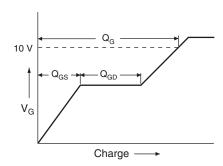


Fig. 13a - Basic Gate Charge Waveform

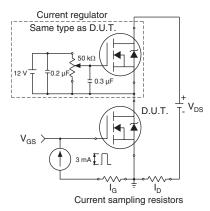
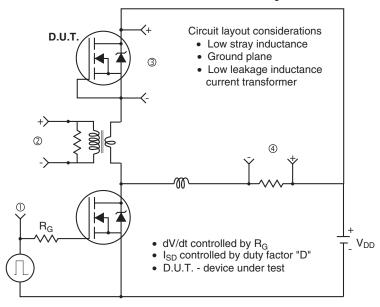
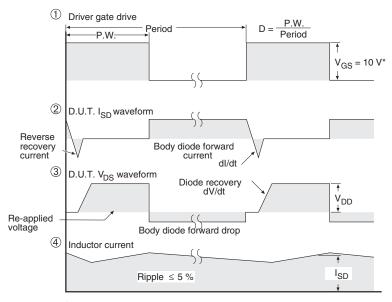


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit





* V_{GS} = 5 V for logic level and 3 V drive devices

Fig. 14 - For N-Channel

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